

**Notice of References Cited**

Application/Control No.

09/724,025

Applicant(s)/Patent Under  
Reexamination  
HERRING ET AL.

Examiner

Edward R. Cosimano

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Art Unit

3629

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*	N	WO 2002/45315 A2	06-2002	WIPO	Herring et al	
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**NON-PATENT DOCUMENTS**

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	U	"Optimal Sequence Testing Scheme for VLSI Circuits": IBM Technical Disclosure Bulletin, 01 April 1987, vol. 29, no. 11, pages 4711-4713.
	V	ROEMER et al: "Advanced diagnostics and prognostics for gas turbine engines risk assessment", 2000 IEEE Aerospace Conference Proceedings (Cat. No. 00TH8484) 18-25 March 2000, Part vol. 6, pages 345-53.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.